## APPLICATION DATA SHEET

Electronic Version 0.0.11

Stylesheet Version: 1.0

Attorney Docket Number: 102847-36

Publication Filing Type:

new-utility

Application Type:

utility

Title of Invention:

METHOD FOR EXAMINING STRUCTURES ON A SEMICONDUCTOR

**SUBSTRATE** 

Attorney Docket Number:

102847-36

**Customer Number Attorney:** 

21125

**Customer Number Correspondence Address:** 

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Continuity Data:

This application is a non-provisional of provisional 60/182,375 2000-02-14 incorporated herein by reference

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